Liquid Chemicals Global Technical Committee Japan TC Chapter

Meeting Summary and Minutes

Japan Standards Spring Meetings 2024

Thursday December 12, 2024, 15:00 -17:00(JST)

Int'l Conference Tower 7F, SEMICON Japan 2024, Tokyo Big Sight, Japan via OVTCCM (Hybrid)

TC Chapter Announcements

Next TC Chapter Meeting

May 16th, 2025, Friday 14:15 - 16:00 @ SEMI Japan Office, Tokyo Japan + Official Virtual Technical Committee Chapter Meeting (OVTCCM)

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Yoshiyuki Fujitani (SCREEN Semiconductor Solutions), Takuya Nagafuchi (Nihon Entegris)

SEMI Staff: Hirofumi Kanno

Company	*Last*	*First*	*Company*	*Last*	*First*
Advance Electric Co., Inc.	Sasao	Kimihito	Particle Measuring Systems, Inc.	Takeshita	Mitsuyoshi
ADVANCE ELECTRIC JAPAN CO.,INC.	Kaiya	Naoko	CKD Corporation	Yasue	Hiroto
AIST-National Institute of Advanced Industrial and Technology	Kato	Haruhisa	RION CO., LTD.	Kondo	Kaoru
Nihon Entegris G.K.	Nagafuchi	Takuya	RION CO., LTD.	Shimmura	Masaki
PILLAR Corporation	Nishi	Takashi	SCREEN Semiconductor Solutions Co., Ltd.	Fujitani	Yoshiyuki
PILLAR Corporation	*Minato*	*Yoji*	Tokyo Dylec Corp	Yanagiuchi	Mamoru
Open Social	*Varwijk*	*Alexander*	NAURA	Cao	Clark
Organo Corporation	Sugawara	Hiroshi	SEMI Japan	Kanno	Hirofumi
Pall Corporation	Nakagawa	Hisashi	SEMI Japan	Sato	Hiroshi
Tokuyama Corporation	Tono	Seiji	SEMI Japan	Kamejinaka	Keiko

Table 2 Leadership Changes

WG/TF/SC/TC Name	*Previous Leader*	*New Leader*
None		

Table 3 Technical Committee Awards

The following two people received the Technical Committee Award.

- Hisashi Nakagawa, Pall Corporation
- Kimihito Sasao, Advance Electric Co., Inc.

Table 4 TC Chapter Structure Changes

Previous WG/TF/SC Name	*New WG/TF/SC Name or Status Change*
None	

Table 5 Ballot Results

Document #	*Document Title*	*Committee Action*
7255	Revision of SEMI C89 - Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS) Type of Document: Major revision to an existing Standard or Safety Guideline	Failed and returned to TF for rework and reballot

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 6 Ratification Ballot Results

None

Table 7 Activities Approved by the GCS between meetings of the TC Chapter

#	*Type*	*SC/TF/WG*	*Details*
7267	SNARF	Liquid-Borne Particle Counter Task Force	Revision to C77-0818, TEST METHOD FOR DETERMING THE COUNTING EFFICIENY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm with title change to TEST METHOD FOR DETERMING THE COUNTING EFFICIENY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 20 nm AND 100 nm
7267	Cycle 7, 2024 and beyond.	Liquid-Borne Particle Counter Task Force	Revision to C77-0818, TEST METHOD FOR DETERMING THE COUNTING EFFICIENY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm with title change to TEST METHOD FOR DETERMING THE COUNTING EFFICIENY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 20 nm AND 100 nm

Table 8 Authorized Activities

None

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:
http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF

Table 9 Authorized Ballots

None

Table 10 SNARF(s) Granted a One-Year Extension

#	*TF*	*Title*	*Expiration Date*
None			

Table 11 SNARF(s) Abolished

#	*TF*	*Title*
None		

Table 12 Standard(s) to receive Inactive Status

Standard Designation	*Title*
None	

Table 13 New Action Items

Item #	*Assigned to*	*Details*
None		

Table 14 Previous Meeting Action Items

Item #	*Assigned to*	*Details*
None		

1 Welcome, Reminders, and Introductions

Takuya Nagafuchi (Nihon Entegris G.K.) called the meeting to order at 15:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01_Meeting Reminders

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion:	Approve the minutes with Table 2 update
By / 2nd:	By: Yoshiyuki Fujitani / SCREEN Semiconductor Solutions Co., Ltd. Second: Hisashi Nakagawa / Pall Corporation
Discussion:	None
Vote:	16-Y 0-N. **Motion Passed.**

Attachment: 02 Liquid Mins_240524_approved FIXED

3 Technical Committee Awards

Technical Committee Award—The committee will award individuals who have made outstanding contributions. The following two people received the Technical Committee Award.

- Hisashi Nakagawa, Pall Corporation
- Kimihito Sasao, Advance Electric Co., Inc.

4 Liaison Reports

4.1 JRSC

Hirofumi Kanno (SEMI Japan) reported for the JRSC. At the previous meeting held on December 9. SEMI Japan staff announced that Global Standards Summit is held at December 12.

4.2 GCS

None

4.3 *Liquid Chemicals North America TC Chapter*

Hirofumi Kanno (SEMI Japan) reported for the NA TC Chapter.

Attachment: 03 NA LChem Liaison Report Nov2024 v1

4.4 *Europe TC Chapter Gases & Liquid Chemicals Joint Global Technical Committee*

Hirofumi Kanno (SEMI Japan) reported no update.

5 SEMI Staff Report

Hirofumi Kanno (SEMI Japan) gave the SEMI Staff Report. Of note:

- SEMI Global2024 & 2025 Calendar of Events
- Global Standards Summit 2024
- SEMI Standards Friendship Party &Award Ceremony
- Regulations & Procedure Manual Updates

Attachment: 04_Staff Report November 2024 v4_ay

6 Ballot Review

6.1 Document Number 7255 Revision SEMI C89-0116 Test Method For Particle Removal Performance Of Liquid Filter Rated Below 30 nm With Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS) with title change to: Test Method For Measuring Particle Removal Performance Of Liquid Filters Rated Below 30 Nm By Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS) – **Failed** and returned to TF for rework and reballot

Attachment: 05 Ballot report 7255 Revision SEMI C89-0116_Liquid Chemicals_v1.0

7 Subcommittee and Task Force Reports

7.1 Liquid Filter TF

Hisashi Nakagawa (Pall Corporation) reported for the *Liquid Filter* Task Force.

- #7255 Revision of SEMI C89-0116: Test Method for Measuring Particle Removal Performance of Liquid Filters Rated Below 30 nm by Inductively Coupled Plasma - Mass Spectroscopy (ICP-MS)
  - 2024/12 Review meeting after ballot
- #7254 Revision of SEMI F110-0712: Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters
  - 2024/12 1st Draft to be prepared -> Postponed to align with #7255 negative comment.
  - 2025 Draft review to global followed by ballot
- #6911 New Standard: Test Method for Metal Removal Performance of Liquid Filter
    - 2025/1H 1st Draft to be prepared followed by Draft review to global
    - 2025/2H Ballot

Attachment: 06 LF-TF Meeting Minutes_20241212_after_TF_meeting

7.2 Liquid-Borne Particle Counter TF

Masaki Shinmura (RION CO., LTD.) reported for the Liquid-Borne Particle Counter Task Force.

He reported that GCS approved the following SNARF (Doc. 7276) and ballot submission. The document will be submitted for Cycle 2, 2025.

- Document 7276, Revision to C77-0818, TEST METHOD FOR DETERMING THE COUNTING EFFICIENY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm with title change to TEST METHOD FOR DETERMING THE COUNTING EFFICIENY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 20 nm AND 100 nm
- Cycle 2, 2025 Critical Date
  - Ballot Submission Date: Thursday, January 23, 2025
  - Voting Period Starts: Tuesday, February 11, 2025
  - Voting Period Ends: Thursday, March 13, 2025

7.3 Trace Metal Analysis for High Pure IPA TF

None

7.4 Valve & Fitting TF

Kimihito Sasao (Advance Electric) explained the situation of the Task Force activities verbally.

8 Old Business

8.1 SNARF Project Period Check

None

8.2 5-year Review

SEMI C82-0713 (Reapproved 0819), Test Method for Particle Removal Performance of Liquid Filter Rated 20 to 50 nm With Liquid-Borne Particle Counter

- Next Liquid Filter task force will discuss the future action on the above document.

9 New Business

None

10 Next Meeting and Adjournment

May 16th, 2025, Friday 14:15 - 16:00 @ SEMI Japan Office, Tokyo Japan + Official Virtual Technical Committee Chapter Meeting (OVTCCM)

See http://www.semi.org/standards-events for the current list of events.

Adjournment: 17:00.

Respectfully submitted by:

Hirofumi Kanno

Standards & EHS

SEMI Japan

Phone: 81.3332.6018

Email: hkanno@semi.org

Minutes tentatively approved by:

Yoshiyuki Fujitani (SCREEN Semiconductor Solutions Co., Ltd.), Co-chair	
Takuya Nagafuchi (Nihon Entegris G.K.), Co-chair	

Table 15 Index of Available Attachments[#1]

Title	*Title*
01_Meeting Reminders	02 Liquid Mins_240524_approved FIXED
03 NA LChem Liaison Report Nov2024 v1	04_Staff Report November 2024 v4_ay
05 Ballot report 7255 Revision SEMI C89-0116_Liquid Chemicals_v1.0	06 LF-TF Meeting Minutes_20241212_after_TF_meeting

Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.